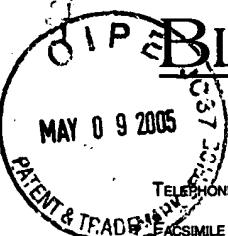


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SEATTLE, WA

April 28, 2005

Commissioner for Patents
PO Box 1450
Alexandria, VA 22313-1450

Certificate
MAY 13 2005

of Correction

Re: **CERTIFICATE OF CORRECTION**
U. S. Letters Patent No. 6,859,587
Issued: February 22, 2005
For: METHOD AND APPARATUS FOR WAFER
LEVEL TESTING OF INTEGRATED
OPTICAL WAVEGUIDE CIRCUITS
Inventor: Nikonov, et al.
Our File No. 42390.P13380

Dear Sir:

Enclosed is the Certificate of Correction (two copies) for the above-referenced patent.
This request for correction is made under rule 322 of the Rules of Practice and 35 U.S.C.
Section 254.

Respectfully submitted,

BLAKELY, SOKOLOFF, TAYLOR & ZAFMAN LLP

Edwin H. Taylor
Reg. No. 25,129

EHT/cgb
Enclosures

MAY 18 2005

UNITED STATES PATENT AND TRADEMARK OFFICE
CERTIFICATE OF CORRECTION

PATENT NO. : 6,859,587

DATED : February 22, 2005

INVENTOR(S) : Nikonov, et al.

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

In column 3, at line 2, before the 1st instance of "wafer", insert --PLC--.

MAILING ADDRESS OF SENDER
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12400 Wilshire Blvd. 7th floor
Los Angeles, CA 90025-1026

PATENT NO. 6,859,587

Certificate of Correction (PTO Form 1050)-Amended

MAY 18 2005